



#3

Docket No.: 87289.1741
Customer No. 30734

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

ELWOOD *et al.*

Serial No. 10/022,194

Filed: December 20, 2001

:
:
:
:
:
: Group Art Unit: 2121
:
: Examiner:

For: EQUIPMENT MONITORING SYSTEM AND METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents and Trademarks
Washington, D. C. 20231

Sir:

RECEIVED
MAR 18 2002
Technology Center 2100

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449.

It is respectfully requested that the documents be expressly considered and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

No further elaboration is believed necessary. Copies of the prior art are submitted herewith in accordance with 37 C.F.R. §1.98(a).

Docket No. 87289.1741



PATENT

AUTHORIZATION

This Information Disclosure Statement is being filed before receipt of the first Office Action. No fee is required. The Commissioner is hereby authorized to charge any additional fees which may be required for this submission, or credit any overpayment to deposit account no. 50-2036.

Respectfully submitted,

BAKER & HOSTETLER LLP

A handwritten signature in black ink, appearing to read 'Dennis P. Cawley', written over a horizontal line.

Dennis P. Cawley
Registration No. 44,598

Date: 3/12/2002
Baker & Hostetler LLP
Washington Square, Suite 1100
1050 Connecticut Avenue, N.W.
Washington, D.C. 20036
Telephone: (202) 861 1500
Facsimile: (202) 861 1783

RECEIVED
MAR 18 2002
Technology Center 2100



LIST OF ART CITED BY APPLICANT

(PTO-1449)

ATTY. DOCKET NO.
87289.1741SERIAL NO.
10/022,194APPLICANT
ELWOOD et al.FILING DATE
12/20/01GROUP
2121

U.S. PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A		6,262,550	07/17/01	Kliman et al.	318	565	12/17/99
B		4,125,892	11/14/78	Fakuda et al.	364	200	06/29/77
C		4,032,907	06/28/77	Young	340	213R	08/08/75
D							
E							
F							
G							
H							
I							
J							
K							
L							
M							
N							
O							
P							
Q							
R							
S							
T							

RECEIVED

MAR 18 2002

Technology Center 2100

FOREIGN PATENT DOCUMENTS

	EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
U							
V							
W							
X							
Y							
Z							
AA							
BB							
CC							
DD							
EE							
FF							
GG							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

HH		
II		
JJ		
KK		
LL		
MM		
NN		

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.